

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/597,496 MAEKAWA ET AL.	
		Examiner	Art Unit GREG BENGZON	2444 Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,072,337 B1	07-2006	Arutyunov et al.	370/389
*	B	US-6,614,809 B1	09-2003	Verma et al.	370/469
*	C	US-2008/0162726 A1	07-2008	Hoover et al.	709/245
*	D	US-2004/0030804 A1	02-2004	Wiget et al.	709/245
*	E	US-2004/0205246 A1	10-2004	Park, Soo-hong	709/245
*	F	US-2005/0114880 A1	05-2005	Gould, Kenneth	725/025
*	G	US-7,395,354 B2	07-2008	Keane et al.	709/245
*	H	US-6,463,475 B1	10-2002	Calhoun, Patrice R.	709/227
*	I	US-2004/0162915 A1	08-2004	Caronni et al.	709/245
*	J	US-7,289,504	10-2007	Hippelainen et al.	370/392
*	K	US-2004/0236855	11-2004	Peles, Amir	709/227
*	L	US-2007/0097977	05-2007	Boden et al.	370/392
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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